

<b>Search Notes</b> 				<b>Application/Control No.</b> 10/047,540 <b>Examiner</b> Annan Q. Shang	<b>Applicant(s)/Patent under Reexamination</b> RITZ ET AL. <b>Art Unit</b> 2623	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner		DATE	EXMR
725	4,10- 14,34- 36,47,60,6 1,87,104	9/11/2006	A.S			
725	109	9/11/2006	A.S			
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			